

Gul Rehman

List of Publications by Year in descending order

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Version: 2024-02-01

10
papers

479
citations

1307594

7
h-index

1372567

10
g-index

10
all docs

10
docs citations

10
times ranked

629
citing authors

#	ARTICLE	IF	CITATIONS
1	First principle study of band gap nature, spontaneous polarization, hyperfine field and electric field gradient of desirable multiferroic bismuth ferrite (BiFeO ₃). Journal of Physics and Chemistry of Solids, 2021, 148, 109737.	4.0	22
2	Electronic and optical properties of group IIA-IVB cubic perovskite oxides: Improved TB-mBJ study. Chemical Physics Letters, 2020, 757, 137887.	2.6	6
3	Intriguing electronic and optical properties of M ₂ CX ₂ (M = Mo, W; X = O, F) MXenes and their van der Waals heterostructures. Chemical Physics Letters, 2019, 731, 136614.	2.6	13
4	Van der Waals heterostructures of blue phosphorene and scandium-based MXenes monolayers. Journal of Applied Physics, 2019, 126, .	2.5	14
5	Intriguing electronic structures and optical properties of two-dimensional van der Waals heterostructures of Zr ₂ CT ₂ (T = O, F) with MoSe ₂ and WSe ₂ . Journal of Materials Chemistry C, 2018, 6, 2830-2839.	5.5	73
6	Electronic structure, optical and photocatalytic performance of SiCâ€“MX ₂ (M = Mo, W) Tj ETQq0 0 0 rgBT /Overlock 10 T 24168-24175.	2.8	85
7	Theoretical studies of the electronic structure and magnetic properties of aluminum-rich intermetallic alloy Al ₁₃ Fe ₄ . International Journal of Modern Physics B, 2018, 32, 1850201.	2.0	4
8	Structural, electronic and optical properties of CsPbX ₃ (X=Cl, Br, I) for energy storage and hybrid solar cell applications. Journal of Alloys and Compounds, 2017, 705, 828-839.	5.5	203
9	Structural, Mechanical and Optoelectronic Properties of Y ₂ M ₂ O ₇ (M = Ti, V and Nb) Pyrochlores: A First Principles Study. Journal of Electronic Materials, 2017, 46, 4640-4648.	2.2	5
10	Electronic Band Structures of the Highly Desirable IIIâ€“V Semiconductors: TB-mBJ DFT Studies. Journal of Electronic Materials, 2016, 45, 3314-3323.	2.2	54